

**Supplementary figures for;**

**Comparison of growth texture in round Bi2212 and flat Bi2223 wires and its relation to high critical current density development**

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**Figure captions**

Figure S1 600  $\mu\text{m}$  long ND-IPF cross section montage of the Bi2212 filament that is split into 5 images. The images are continuous according to the numbering order. The right end of one image connects to the left end of the following image.

Figure S2 The ND-IPF map of a longitudinal cross section of Bi2212 filament. The two locations on the single Bi2212 grain are denoted as A and B, for which the schematic unit cells are shown to illustrate the crystallographic orientations. From the location A to B, the Bi2212 ab-planes twist  $\sim 30^\circ$  around the wire direction, and bend  $\sim 5^\circ$  upward by plastic deformation that occurs during grain formation and growth at high temperature.

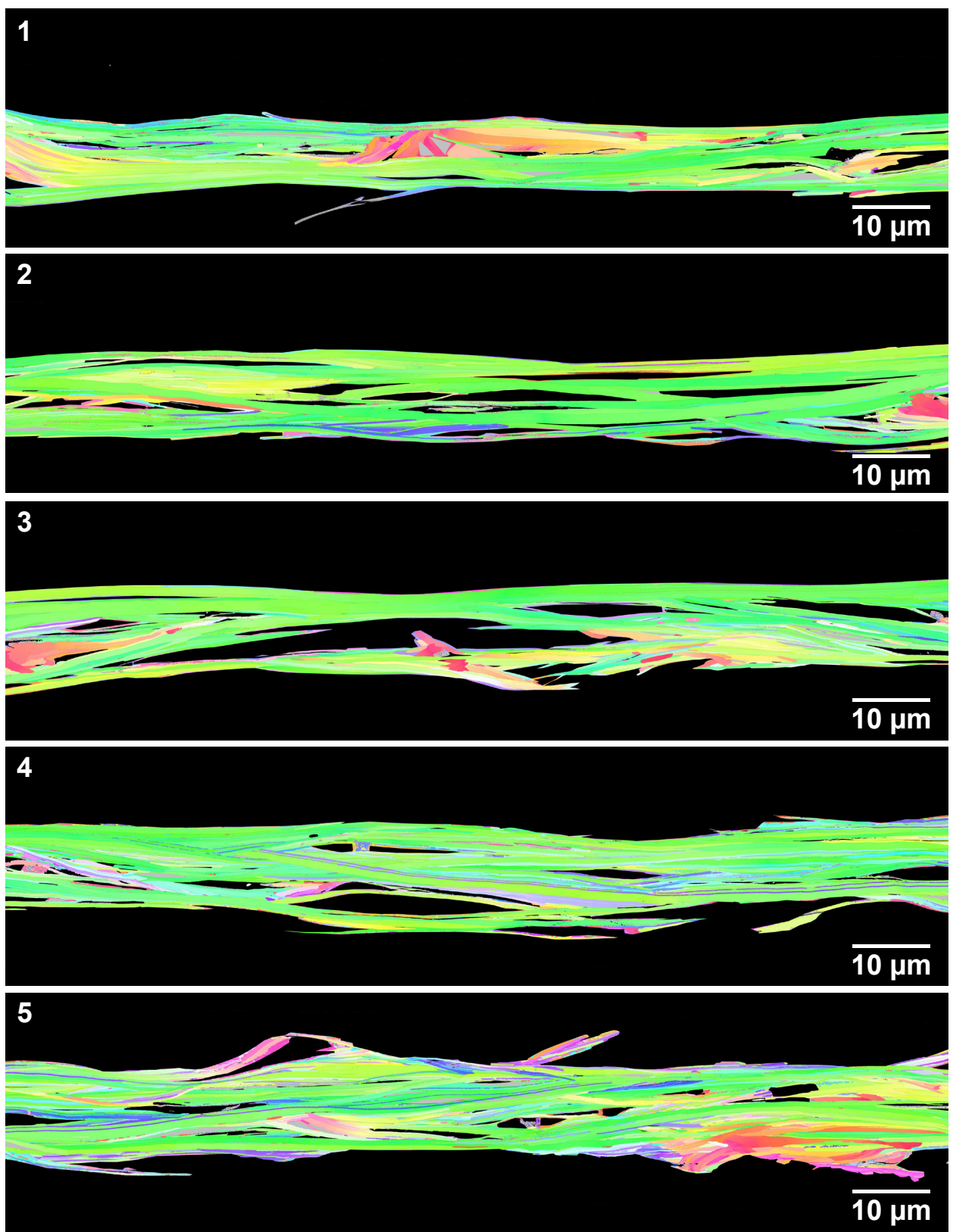


Figure S1

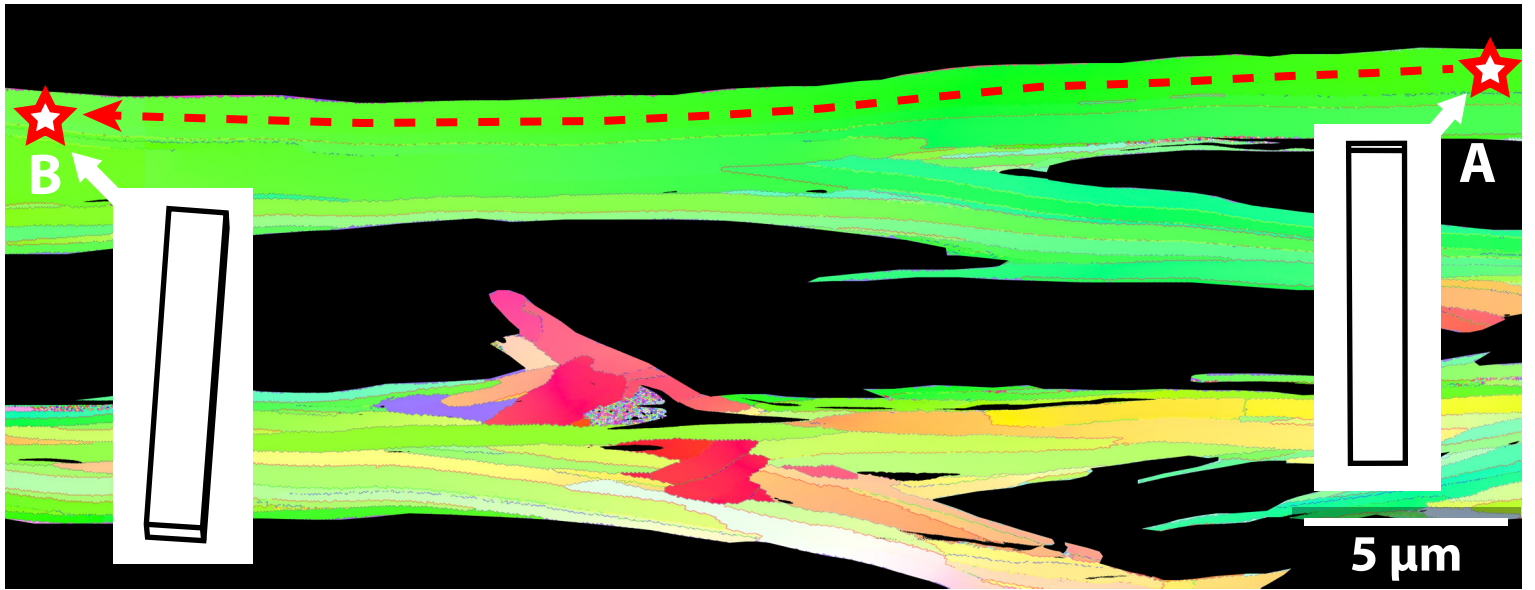


Figure S2